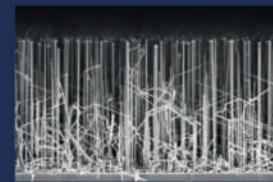


At NNFC, contamination controlled and dedicated furnaces are available to perform high temperature processes like deposition, dopant diffusion and metallization.



Conformal deposition in a trench



Ge nanowires grown on Si

## FURNACES

- 12 furnace tubes for dedicated processes
- Max temp 1100 °C
- Sample Size (small pieces to 4" full wafers)
- Batch processing (25 wafers at a time)
- SiO<sub>2</sub>, Poly-Si, Si<sub>3</sub>N<sub>4</sub>, SiGe, Doping and Diffusion



- Rapid Thermal Processing systems
- Up to 1200 °C, ramp rates 30° - 200 °C/sec
- N<sub>2</sub>, H<sub>2</sub>, N<sub>2</sub>O, NH<sub>3</sub> and O<sub>2</sub> gas lines
- Contact alloying, Oxidation and Nitridation
- Silicidation

### CONTACT US

**NATIONAL NANO FABRICATION CENTRE**  
CENTRE FOR NANO SCIENCE AND  
ENGINEERING (CENSE)

Indian Institute of Science  
Bengaluru, Karnataka, India  
nnfc.cense@iisc.ac.in  
ctcense@iisc.ac.in  
+91-80-2293 3276  
+91-80-2293 3291  
www.nnfc.cense.iisc.ac.in



### RF & DC SPUTTER TOOLS

- Dedicated tools for metals and dielectrics
- More than 50 materials to sputter
- Multi-target and multi-wafer holders with planetary system
- 50° - 600°C substrate temperature range

## CVD AND THIN FILMS

### PECVD

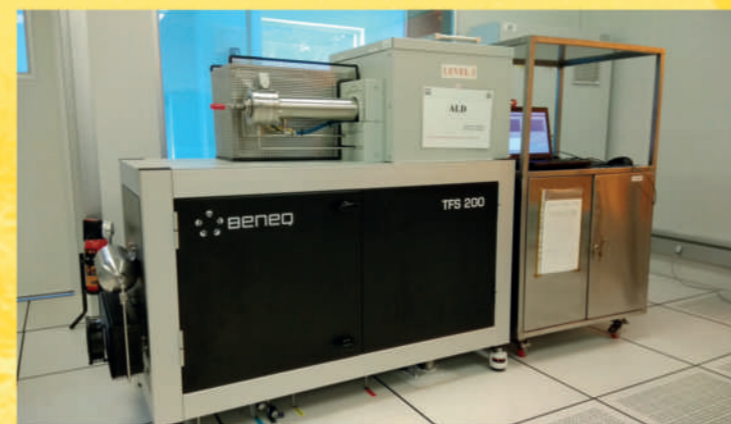
- 6" wafers to small pieces
- Substrate temperature up to 400 °C
- Gases - H<sub>2</sub>, SiH<sub>4</sub>, GeH<sub>4</sub>, CH<sub>4</sub>, NH<sub>3</sub>, CF<sub>4</sub>, N<sub>2</sub>O, N<sub>2</sub>, Ar, 2% B<sub>2</sub>H<sub>6</sub>/Ar, 1% PH<sub>3</sub>/Ar
- Materials: a-Si, SiO<sub>2</sub>, Si<sub>3</sub>N<sub>4</sub>, SiC and SiGe



Conformal trench coverage



Conformal step coverage



### ATOMIC LAYER DEPOSITION

- Up to 8" wafer
- Substrate temperature range: 25° - 400 °C
- Materials: Al<sub>2</sub>O<sub>3</sub>, TiO<sub>2</sub> and ZnO



### E-BEAM EVAPORATION

- Dual e-gun and dual-hearth system
- Multi wafer holders (four) with planetary system  
Substrate temp up to 300 °C
- Max 6" wafers to small pieces
- Co-evaporation and ion-assisted deposition possible
- 46 materials
- Ion-etching for pre-cleaning substrate



### IN-LINE CHARACTERIZATION



- Ellipsometer  
12" wafer capability  
Standard models for many materials
- Surface profiler  
Step height and 3D mapping
- Curvature profiler
- Contactless Hall mobility
- Four-point probe

### WHAT WE OFFER

- Basic and advanced training in process technologies
- Access to a large range of process equipment in our cleanroom
- Consultancy and services ranging from unit or integrated process steps all the way up to prototyping a device



# NATIONAL NANO FABRICATION CENTRE

# OVERVIEW

National Nano Fabrication Centre (NNFC) is a national facility open to public and private academic institutes, private industries, public sector undertaking and Indian strategic sector.

NNFC is a class 100 and class 1000 state-of-the-art fabrication facility spanning over an area of 14,000 sq ft, enabling More-Moore and More-than-Moore technologies including MEMS/NEMS, photonics, PV, spintronics, sensors, actuators and materials development.

Supported by 24/7 cleanroom utility and dedicated staff members, NNFC is capable of realizing micro and nanoscale devices on various substrates that include Si, GaN, SiC, Quartz, Glass, Graphene and III-V semiconductors.

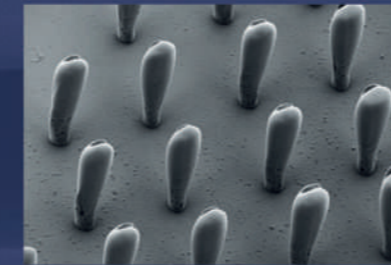


## DIRECT WRITING AND MASK MAKING

- Minimum features down to 1  $\mu\text{m}$
- Alignment accuracy - 200 nm
- Sample/mask size: 6" wafer/mask down to small pieces
- Design file format - GDS2/CIF/DXF



SU8 structure array



1 micron gap between large structures

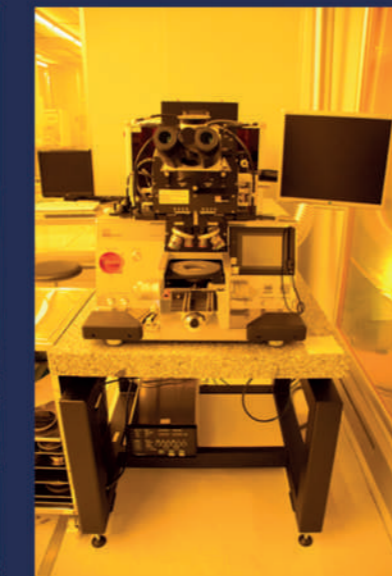
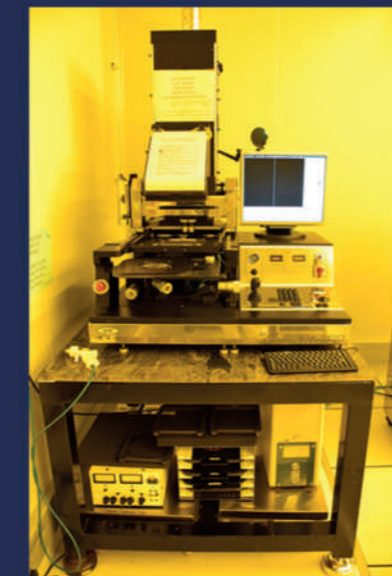
## E-BEAM LITHOGRAPHY

- Accelerating voltage: 30 kV
- Apertures: 7.5, 10, 20, 30, 60, 120  $\mu\text{m}$
- Minimum feature size: Sub-10 nm
- SEM feature
- Spot size with 30  $\mu\text{m}$  aperture  
@ 1 kV: 4 nm  
@ 20 kV: 2.1 nm

Housed in Class 100 area in the cleanroom, the lithography bay has several tools with minimum feature size patterning capability ranging from a few microns all the way down to a few nanometers.



# LITHOGRAPHY



- Minimum features down to 1  $\mu\text{m}$
- Alignment accuracy  
1  $\mu\text{m}$  front side  
5  $\mu\text{m}$  back side
- Sample size - 6" wafers down to small pieces
- Design file format - GDS2/CIF/DXF

1-micron lines



2-micron squares



Bi-layer lift-off process



## WAFER BONDER

- Up to 4" substrate and quarter wafer pieces can be handled
- Types of bonding available:  
Eutectic bonding (Si-Au-Si)  
Anodic bonding (Si-Glass)  
Fusion bonding (Si-Si)



Bi-layer for lift-off process

Contact pads for nanowires

50 nm structures

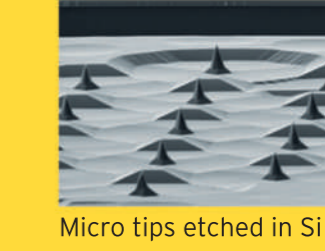


20 nm lines with 20 nm spacing



Dedicated wet benches to avoid cross-contamination

In NNFC cleanroom, dedicated wet processing stations are available for wafer cleaning and etching various materials.



Micro tips etched in Si



V-Groove structures in Si

## WET ETCH



Critical Point Drier (CPD)



HF vapour etch

Critical point drying and vapour-phase HF etching render stiction-free released structures.



Released RF MEMS switch



Released cantilevers

A special Deep Reactive Ion Etch (DRIE) equipment is used for through-Si wafer etching for MEMS applications.

## DRY ETCH



RIE tools

- Dedicated FI and CI based chemistry
- Si, III-V, dielectric and metal etching
- Isotropic and anisotropic
- Input gases -  $\text{O}_2$ , Ar,  $\text{C}_4\text{F}_8$ ,  $\text{N}_2$ ,  $\text{H}_2$ ,  $\text{Cl}_2$ ,  $\text{BCl}_3$ ,  $\text{CH}_4$ ,  $\text{HBr}$ ,  $\text{SF}_6$ ,  $\text{CHF}_3$
- 6" wafers to small pieces



Micro mirrors



Nano pillars etched in Si



DRIE tool



Floating rings etched in Si

- Dedicated to Si deep etch
- Through Si wafer via etch can be done
- Maximum Si etch rate ~ 30  $\mu\text{m}/\text{min}$
- Up to 50 aspect ratio in etch
- 6" wafers to small pieces

## OPTICAL LITHOGRAPHY

